

Date	December 10, 2020			
China Time		Speakers	Institute/Company	Presentation title
15:00-15:10	Welcome speech	Mario Lanza Keibock Lee	General Chair, King Abdullah University of Science and Technology, Saudi Arabia Vice President, Park Systems, Korea & Chief Editor of NanoScientific	
Session I Host: Fei Hui				
15:10-15:40	Special Guest Interview	Sean Joseph O'Shea	A*STAR, Singapore	Inventor Interview of Conductive Atomic Force Microscopy
15:40-16:10	Invited talk	Guenther Benstetter	Deggendorf Institute of Technology, Germany	Recent Trends in Characterization of Nanoelectronic Materials and Devices with Scanning Probe Microscopy
16:10-16:40		Umberto Celano	IMEC, Belgium	Electrical AFM for Nanoelectronics
16:40-17:10		Sangjoon Cho	Park Systems, Korea	Non-contact AFM with Self-Optimizing and Pinpoint Scan Control for Quantitative Nano-Metrology
17:10-17:40		Miguel Munoz Rojo	University of Twente, Netherlands	Nanoscale Thermal Mapping of Electronic Devices
17:40-19:00	Dinner time	Individual dinner at your own place and reconnect		
Session II Host: Mario Lanza				
19:00-19:30	Invited talk	Filippo Giannazzo	National Research Council of Italy, Italy	Conductive Atomic Force Microscopy of 2D Materials and Heterostructures for Nanoelectronics
19:30-20:00		Alok Ranjan	Singapore University of Technology and Design, Singapore	Conduction Atomic Force Microscopy for Gate Dielectric Reliability Analysis
20:00-20:30		Chao Wen	Soochow University, China (2020 Park AFM Scholarship Winner)	Calcium Fluoride: an Outstanding High-k Dielectric for 2D Electronics
20:30-21:00	Park live demo	Charles Kim	Park Systems, Korea	A Comparative Study for Surface Potential Mapping Using KPFM
21:00-21:30	Round-table discussion	Moderator: Mario Lanza; Panelist: Umberto Celano, Filippo Giannazzo, Miguel Munoz Rojo, Sang-joon Cho		
21:30-21:40	Closing remarks	Mario Lanza	General Chair, King Abdullah University of Science and Technology, Saudi Arabia	